

## Special session (Innovative Practices Track)

# Innovations in Test Automation

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### Abstract

Test automation has been a cornerstone of the manufacturing test industry, much as electronic design automation has been to the semiconductor industry. Thus, it is fair to say that test automation providers will have a significant role to play in addressing the challenges involved in testing system-chips of the future. This session contains presentations that examine the test challenges presented by system-level integration, from the perspective of the providers of test tools and methodologies. The presenters will highlight innovations that will lead to improved test flows, addressing critical issues such as testing cost, test application time, and reuse of test hardware for silicon debug.